

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KIM, CHANG-SEOB	
		Examiner	Art Unit	Page 1 of 1
U.S. PATENT DOCUMENTS				

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0171383	08-2005	Arai et al.	568/006
	B	US-			
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	E	US-			
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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